

FDR4410 N-Channel Enhancement Mode Field Effect Transistor

General Description

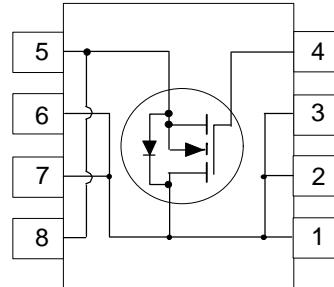
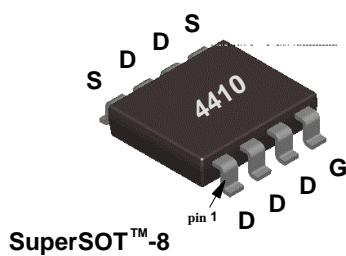
The FDR4410 has been designed as a smaller, low cost alternative to the popular Si4410DY.

The SuperSOT™-8 package is 40% smaller than the SO-8 package.

The SuperSOT™-8 advanced package design and optimized pinout allow the typical power dissipation to be similar to the bigger SO-8 package.

Features

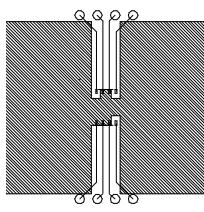
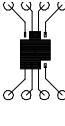
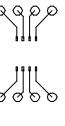
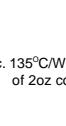
- 9.3 A, 30 V. $R_{DS(ON)} = 0.013 \Omega$ @ $V_{GS} = 10$ V
 $R_{DS(ON)} = 0.020 \Omega$ @ $V_{GS} = 4.5$ V.
- High density cell design for extremely low $R_{DS(ON)}$.
- Proprietary SuperSOT™-8 small outline surface mount package with high power and current handling capability.



Absolute Maximum Ratings $T_A = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	FDR4410	Units
V_{DSS}	Drain-Source Voltage	30	V
V_{GSS}	Gate-Source Voltage	± 20	V
I_D	Drain Current - Continuous - Pulsed	9.3 40	A
P_D	Maximum Power Dissipation (Note 1a) (Note 1b) (Note 1c)	1.8 1 0.9	W
T_J, T_{STG}	Operating and Storage Temperature Range	-55 to 150	$^\circ\text{C}$
THERMAL CHARACTERISTICS			
R_{QJA}	Thermal Resistance, Junction-to-Ambient (Note 1a)	70	$^\circ\text{C}/\text{W}$
R_{QJC}	Thermal Resistance, Junction-to-Case (Note 1)	20	$^\circ\text{C}/\text{W}$

Electrical Characteristics ($T_A = 25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
OFF CHARACTERISTICS						
V_{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}$, $I_D = 250 \mu\text{A}$	30			V
$\Delta V_{DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	$I_D = 250 \mu\text{A}$, Referenced to 25°C		35		$\text{mV}/^\circ\text{C}$
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 24 \text{ V}$, $V_{GS} = 0 \text{ V}$ $T_J = 55^\circ\text{C}$		1	25	μA
I_{GSS}	Gate - Body Leakage Current	$V_{GS} = 20 \text{ V}$, $V_{DS} = 0 \text{ V}$		100		nA
I_{GSS}	Gate - Body Leakage, Reverse	$V_{GS} = -20 \text{ V}$, $V_{DS} = 0 \text{ V}$		-100		nA
ON CHARACTERISTICS (Note 2)						
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 250 \mu\text{A}$	1	1.5	2	V
$\Delta V_{GS(\text{th})}/\Delta T_J$	Gate Threshold Voltage Temp.Coefficient	$I_D = 250 \mu\text{A}$, Referenced to 25°C		-4.4		$\text{mV}/^\circ\text{C}$
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS} = 10 \text{ V}$, $I_D = 9.3 \text{ A}$ $T_J = 125^\circ\text{C}$	0.011	0.013		Ω
		$V_{GS} = 4.5 \text{ V}$, $I_D = 5 \text{ A}$	0.017	0.02		
$I_{D(\text{ON})}$	On-State Drain Current	$V_{GS} = 10 \text{ V}$, $V_{DS} = 5 \text{ V}$	20			A
g_{FS}	Forward Transconductance	$V_{DS} = 10 \text{ V}$, $I_D = 9.3 \text{ A}$		25		S
DYNAMIC CHARACTERISTICS						
C_{iss}	Input Capacitance	$V_{DS} = 15 \text{ V}$, $V_{GS} = 0 \text{ V}$, $f = 1.0 \text{ MHz}$		1170		pF
C_{oss}	Output Capacitance			627		pF
C_{rss}	Reverse Transfer Capacitance			180		pF
SWITCHING CHARACTERISTICS (Note 2)						
$t_{D(on)}$	Turn - On Delay Time	$V_{DD} = 25 \text{ V}$, $I_D = 1 \text{ A}$, $V_{GS} = 10 \text{ V}$, $R_{\text{GEN}} = 6 \Omega$		12	22	ns
t_r	Turn - On Rise Time			11	20	ns
$t_{D(off)}$	Turn - Off Delay Time			41	66	ns
t_f	Turn - Off Fall Time			34	55	ns
Q_g	Total Gate Charge	$V_{DS} = 15 \text{ V}$, $I_D = 9.3 \text{ A}$, $V_{GS} = 10 \text{ V}$		36	50	nC
Q_{gs}	Gate-Source Charge			4.5		nC
Q_{gd}	Gate-Drain Charge			10		nC
DRAIN-SOURCE DIODE CHARACTERISTICS AND MAXIMUM RATINGS						
I_s	Maximum Continuous Drain-Source Diode Forward Current			1.5		A
V_{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}$, $I_s = 1.5 \text{ A}$ (Note 2)		0.72	1.2	V
Notes:						
1. R_{BJA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{BJC} is guaranteed by design while R_{BCA} is determined by the user's board design. R_{BJA} shown below for single device operation on FR-4 board in still air.						
 <p>Scale 1 : 1 on letter size paper</p>						
<p>a. $70^\circ\text{C}/\text{W}$ on a 1 in^2 pad of 2oz copper.</p> 						
<p>b. $125^\circ\text{C}/\text{W}$ on a 0.026 in^2 pad of 2oz copper.</p> 						
<p>c. $135^\circ\text{C}/\text{W}$ on a 0.005 in^2 pad of 2oz copper.</p> 						
2. Pulse Test: Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2.0\%$.						

Typical Electrical Characteristics

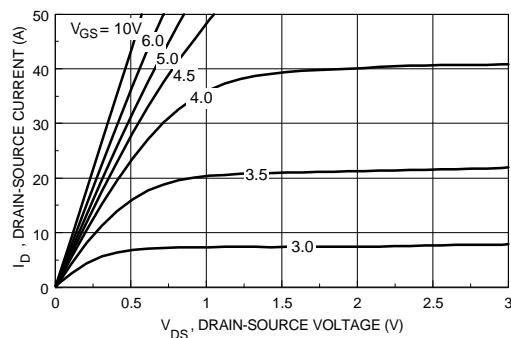


Figure 1. On-Region Characteristics.

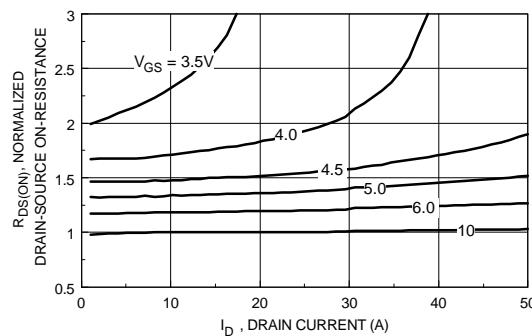


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

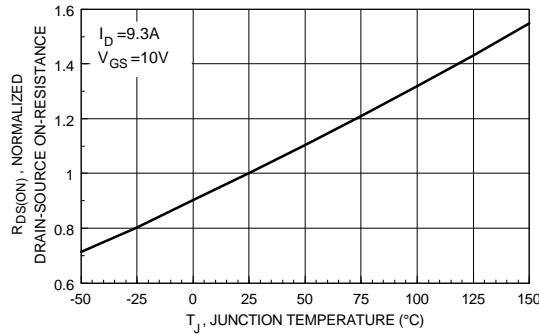


Figure 3. On-Resistance Variation with Temperature.

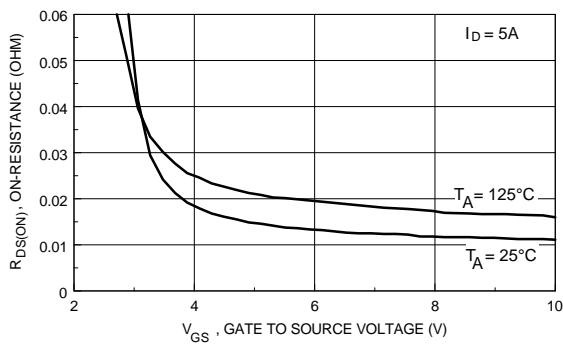


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

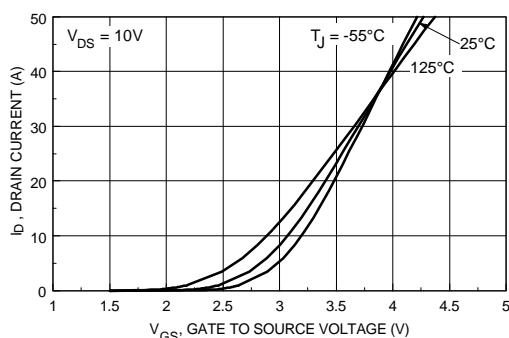


Figure 5. Transfer Characteristics.

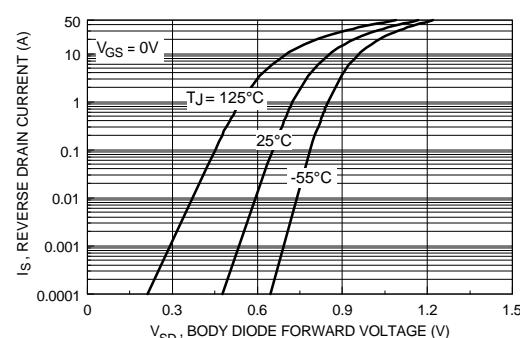


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Electrical Characteristics (continued)

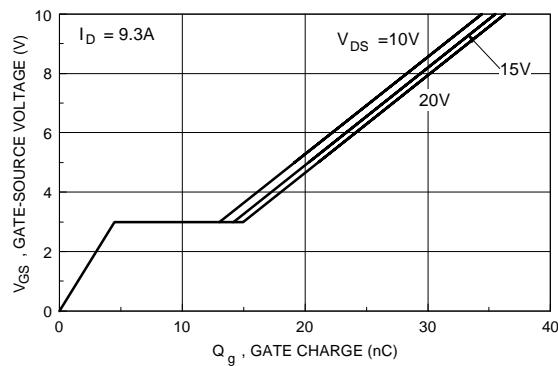


Figure 7. Gate Charge Characteristics.

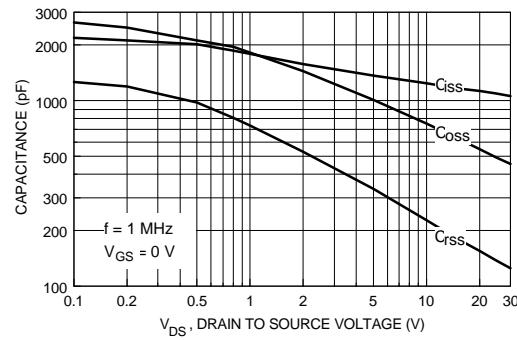


Figure 8. Capacitance Characteristics.

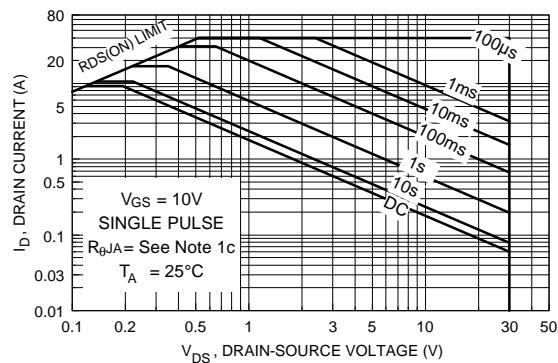


Figure 9. Maximum Safe Operating Area.

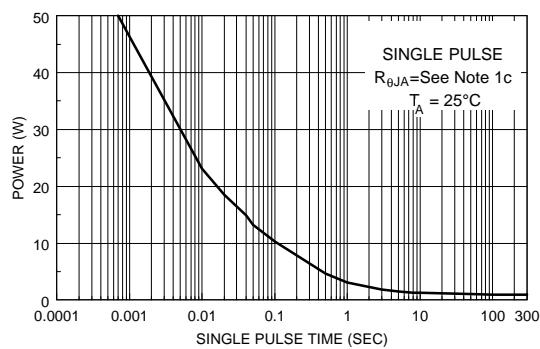


Figure 10. Single Pulse Maximum Power Dissipation.

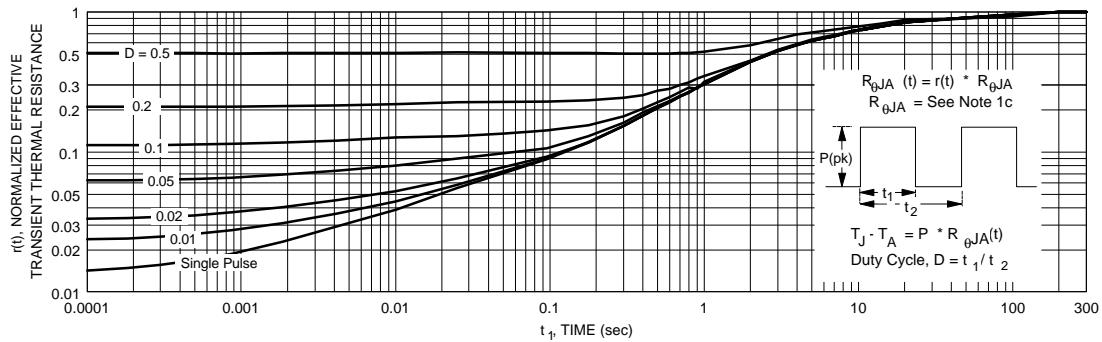


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in note 1c.
Transient thermal response will change depending on the circuit board design.